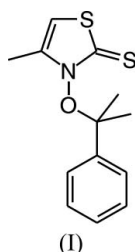


Jens Hartung,* Nina Schneiders
and Uwe BergsträsserOrganische Chemie, Fachbereich Chemie,
Technische Universität Kaiserslautern, Erwin-
Schrödinger-Strasse, D-67663 Kaiserslautern,
GermanyCorrespondence e-mail:
hartung@chemie.uni-kl.de

Key indicators

Single-crystal X-ray study
 $T = 293$ K
Mean $\sigma(\text{C}-\text{C}) = 0.004$ Å
Disorder in main residue
 R factor = 0.035
 wR factor = 0.085
Data-to-parameter ratio = 13.6For details of how these key indicators were
automatically derived from the article, see
<http://journals.iucr.org/e>.3-(1-Methyl-1-phenylethoxy)-1,3-thiazole-
2(3*H*)-thione: a tertiary thiohydroxamic
acid *O*-esterThe steric demand of a tertiary alkyl substituent attached to the thiohydroxamate O atom in the title compound, $\text{C}_{13}\text{H}_{15}\text{NOS}_2$, is reflected in a widening of the associated N—O—C angle [$116.4(2)^\circ$]. Close contacts along [100] indicate C—H \cdots S interactions in the crystal structure.Received 31 August 2006
Accepted 19 September 2006

Comment

3-(1-Methyl-1-phenylethoxy)-1,3-thiazole-2(3*H*)-thione, (I), is a photolabile compound that undergoes facile *N,O*-homolysis upon UV-vis photolysis or if heated in the presence of a free radical initiator (Hartung *et al.*, 2006). The compound was prepared and investigated by X-ray diffraction in order to study the hitherto unknown geometry of tertiary thiohydroxamic acid *O*-esters.The cumyl substituent of (I) is rotated by $95.6(2)^\circ$ from the plane defined by the thiohydroxamate entity and the *N,C*-bridging vinyl-thiyl subunit, as measured by the appropriate torsion angles (Table 1). The unit cell comprises a 1:1 mixture of *P*- and *M*-rotamers with respect to the configuration about the stereogenic N—O axis. In CDCl_3 solution (298 K), a fast rotation about this axis occurs, as is evident from the topomerization of prochiral substituents, *i.e.* C_8H_3 and C_9H_3 .

Bond lengths and angles within the heterocyclic core and those associated with the thiohydroxamate functionality

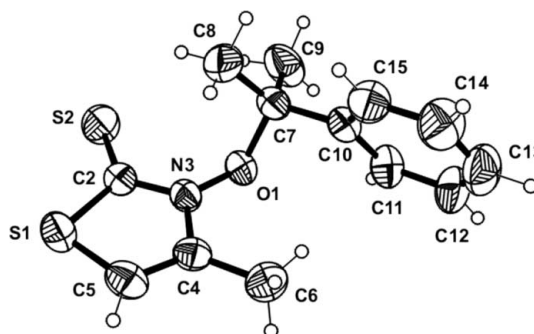


Figure 1

The molecular structure of (I). Displacement ellipsoids are plotted at the 50% probability level. Only one disorder component is shown.

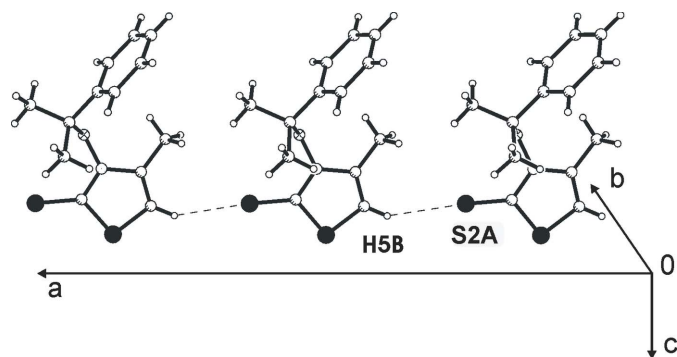


Figure 2
The packing of (I) in the crystal structure, viewed approximately along [010]. Hydrogen bonds are drawn as dashed lines.

(Table 1) correspond to values reported previously for a secondary *N*-alkoxy (Hartung *et al.*, 2003) and an *N*-(alkoxy-carbonyloxy) (Hartung *et al.*, 2005) derivative of *N*-hydroxy-4-methylthiazole-2(3*H*)thione. The major difference between the reference data and those of compound (I) is due to a significant widening of the N3—O1—C7 angle [116.4 (2) °]. The origin of this feature is probably associated with the steric demand of the cumyl substituent attached to O1.

The packing of (I) in the unit cell ($Z = 4$, $P2_1/c$) leads to close H5B \cdots S2ⁱ (2.93 Å) contacts along [100] (Fig. 2 and Table 2). The separation of these atoms and the associated angle at H5B indicate C—H \cdots acceptor interactions between C5H and C=S (Steiner, 1996; Hartung *et al.*, 2005).

Experimental

2-Phenyl-2-propanol (1.10 g, 8.08 mmol), CuCl (16.0 mg, 0.162 mmol) and diisopropyl carbodiimide (1.02 g, 8.08 mmol) were stirred in anhydrous dichloromethane (5 ml) for 24 h. A solution of *N*-hydroxy-4-methylthiazole-2(3*H*)-thione (1.31 g, 8.89 mmol) (Barton *et al.*, 1986) in anhydrous dichloromethane (20 ml) was added at 203 K. The reaction mixture was stirred at 293 K for 45 h. The solids were filtered off and the solvent was removed under reduced pressure. The residue was purified by column chromatography [SiO₂, pentane–diethyl ether, 2:1 (v/v), $R_f = 0.44$] to afford colourless crystals of (I) (yield 70.0 mg, 0.26 mmol, 3%). Crystals suitable for X-ray analysis were obtained from a saturated solution of (I) in diethyl ether (m.p. 379 K). Analysis, calculated for C₁₃H₁₅NOS₂: C 58.83, H 5.70, N 5.28%; found: C 58.98, H 5.68, N 5.26%.

Crystal data

C ₁₃ H ₁₅ NOS ₂	$Z = 4$
$M_r = 265.38$	$D_x = 1.294 \text{ Mg m}^{-3}$
Monoclinic, $P2_1/c$	Mo $K\alpha$ radiation
$a = 7.7504$ (16) Å	$\mu = 0.37 \text{ mm}^{-1}$
$b = 18.363$ (4) Å	$T = 293$ (2) K
$c = 9.788$ (2) Å	Prism, colourless
$\beta = 102.16$ (3)°	$0.35 \times 0.25 \times 0.20 \text{ mm}$
$V = 1361.9$ (5) Å ³	

Data collection

Stoe IPDS diffractometer	2099 independent reflections
φ scans	1278 reflections with $I > 2\sigma(I)$
Absorption correction: none	$R_{\text{int}} = 0.090$
10870 measured reflections	$\theta_{\text{max}} = 24.2^\circ$

Refinement

Refinement on F^2
 $R[F^2 > 2\sigma(F^2)] = 0.035$
 $wR(F^2) = 0.085$
 $S = 0.92$
 2099 reflections
 154 parameters

H-atom parameters constrained
 $w = 1/[\sigma^2(F_o^2) + (0.0355P)^2]$
 where $P = (F_o^2 + 2F_c^2)/3$
 $(\Delta/\sigma)_{\text{max}} < 0.001$
 $\Delta\rho_{\text{max}} = 0.19 \text{ e \AA}^{-3}$
 $\Delta\rho_{\text{min}} = -0.22 \text{ e \AA}^{-3}$

Table 1

Selected geometric parameters (Å, °).

S1—C2	1.720 (3)	C2—N3	1.362 (3)
S1—C5	1.727 (3)	N3—C4	1.406 (3)
O1—N3	1.370 (2)	C4—C5	1.317 (4)
O1—C7	1.511 (3)	C4—C6	1.487 (4)
S2—C2	1.654 (2)		
C2—S1—C5	91.99 (13)	C2—N3—C4	116.9 (2)
N3—O1—C7	116.41 (16)	O1—N3—C4	121.86 (19)
N3—C2—S2	128.04 (19)	C5—C4—N3	110.2 (2)
N3—C2—S1	107.55 (16)	C5—C4—C6	129.0 (2)
S2—C2—S1	124.40 (15)	N3—C4—C6	120.7 (2)
C2—N3—O1	120.20 (18)	C4—C5—S1	113.1 (2)
S2—C2—N3—O1	−5.9 (3)	C7—O1—N3—C2	95.6 (2)

Table 2

Hydrogen-bond geometry (Å, °).

$D-H\cdots A$	$D-H$	$H\cdots A$	$D\cdots A$	$D-H\cdots A$
C5—H5 \cdots S2 ⁱ	0.93	2.93	3.713 (3)	142

Symmetry code: (i) $x - 1, y, z$.

The H-atom sites at C6 are disordered, probably due to a 0.5:0.5 population of CH₃ rotamers with a skew angle of 60°. The group was refined as a disordered methyl group with six half-occupied geometrically idealized positions for the H atoms. All other H atoms were positioned geometrically and treated as riding atoms, with C—H distances set to 0.96 (for CH₃) or 0.93 Å (Csp^2-H) and with $U_{\text{iso}}(H) = 1.2U_{\text{eq}}(Csp^2-H)$ or $1.5U_{\text{eq}}(CH_3)$.

Data collection: *EXPOSE* in *IPDS Software* (Stoe & Cie, 1998); cell refinement: *EXPOSE*; data reduction: *EXPOSE*; program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL-Plus* (Sheldrick, 1994); software used to prepare material for publication: *SHELXTL-Plus*.

This work was supported by the Deutsche Forschungsgemeinschaft (grant No. Ha1705/5–2) and the Fonds der Chemischen Industrie.

References

- Barton, D. H. R., Crich, D. & Kretschmar, G. (1986). *J. Chem. Soc. Perkin Trans. 1*, pp. 39–55.
- Hartung, J., Gottwald, T. & Schneiders, N. (2006). In preparation.
- Hartung, J., Schneiders, N. & Bergsträsser, U. (2005). *Acta Cryst. E61*, o421–o422.
- Hartung, J., Schwarz, M., Svoboda, I. & Fuess, H. (2003). *Acta Cryst. C59*, o682–o684.
- Sheldrick, G. M. (1994). *SHELXTL-Plus*. Version 5.03. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.
- Sheldrick, G. M. (1997). *SHELXS97* and *SHELXL97*. University of Göttingen, Germany.
- Steiner, T. (1996). *Crystallogr. Rev.* **6**, 1–57.
- Stoe & Cie (1998). *IPDS Software*. Version 2.87. Stoe & Cie, Darmstadt, Germany.